ABSOLUTE MAXIMUM RATINGS

V _{CC} to GND0.3V to +4.1V
IN, ĪN, OUT, OUT, EN,
SEL to GND0.3V to (V _{CC} + 0.3V)
IN_ to IN±3V
Short-Circuit Duration (OUT, OUT)Continuous
Continuous Power Dissipation (T _A = +70°C)
32-Pin TQFP (derate 13.1mW/°C
above +70°C)1047mW

Junction-to-Ambient Thermal Resistance i	n Still Air
32-Pin TQFP	+76.4°C/W
Operating Temperature Range	40°C to +85°C
Junction Temperature	+150°C
Storage Temperature Range	
Soldering Temperature (10s)	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

DC ELECTRICAL CHARACTERISTICS

 $(V_{CC}=3.0V\ to\ 3.6V,\ R_L=100\Omega\ \pm1\%,\ EN_{_}=V_{CC},\ V_{CM}=0.05V\ to\ (V_{CC}-0.6V)\ (MAX9392),\ V_{CM}=0.6V\ to\ (V_{CC}-0.05V)\ (MAX9393),\ T_A=-40^{\circ}C\ to\ +85^{\circ}C,\ unless\ otherwise\ noted.\ Typical\ values\ are\ at\ V_{CC}=3.3V,\ |V_{ID}|=0.2V,\ V_{CM}=1.2V,\ T_A=+25^{\circ}C,\ unless\ otherwise\ noted.)$ (Notes 1, 2, and 3)

PARAMETER	PARAMETER SYMBOL CONDITIONS		MIN	TYP	MAX	UNITS		
LVCMOS/LVTTL INPUTS (EN, _SI	EL_)	•		•				
Input High Voltage	VIH			2.0		Vcc	V	
Input Low Voltage	V _{IL}			0		8.0	V	
Input High Current	lін	$V_{IN} = 2.0V \text{ to}$	Vcc	0		20	μΑ	
Input Low Current	I _I L	$V_{IN} = 0 \text{ to } 0.8$	3V	0		10	μΑ	
DIFFERENTIAL INPUTS (IN, IN)							
Differential Input Voltage	V _{ID}	V _{ILD} ≥ 0 and	V _{IHD} ≤ V _{CC} , Figure 1	0.1		3.0	V	
Input Common Mode Dange	Voi	V _{CM} MAX9392 MAX9393		0.05		V _C C - 0.6	V	
Input Common-Mode Range	VCM			0.6	\	VCC - 0.05		
Input Current	I _{IN} ,	MAX9392	IV _{ID} ≤ 3.0V	-50		+10	μΑ	
Input Current		MAX9393	IV _{ID} I <u>≤</u> 3.0V	-10		+90		
LVDS OUTPUTS (OUT, OUT)								
Differential Output Voltage	V _{OD}	$R_L = 100\Omega$, F	igure 2	250	350	450	mV	
Change in Magnitude of V _{OD} Between Complementary Output States	ΔV _{OD}	Figure 2			1.0	50	mV	
Offset Common-Mode Voltage	V _{OS}	Figure 2		1.125	1.25	1.375	V	
Change in Magnitude of VOS Between Complementary Output States	ΔV _{OS}	Figure 2			1.0	50	mV	

DC ELECTRICAL CHARACTERISTICS (continued)

 $(V_{CC}=3.0V\ to\ 3.6V,\ R_L=100\Omega\ \pm1\%,\ EN_{_}=V_{CC},\ V_{CM}=0.05V\ to\ (V_{CC}-0.6V)\ (MAX9392),\ V_{CM}=0.6V\ to\ (V_{CC}-0.05V)\ (MAX9393),\ T_A=-40^{\circ}C\ to\ +85^{\circ}C,\ unless\ otherwise\ noted.$ Typical values are at $V_{CC}=3.3V,\ |V_{ID}|=0.2V,\ V_{CM}=1.2V,\ T_A=+25^{\circ}C,\ unless\ otherwise\ noted.)$ (Notes 1, 2, and 3)

PARAMETER	SYMBOL	MBOL CONDITIONS		MIN	TYP	MAX	UNITS
Output Short-Circuit Current	llaal	$V_{ID} = \pm 100 \text{mV}$	V_{OUT} or $V_{\overline{OUT}}$ = 0		30	40	m 1
(Either Output Shorted to GND)	llosl	(Note 4)	$V_{OUT} = V_{\overline{OUT}} = 0$		18	24	mA
Output Short-Circuit Current (Outputs Shorted Together)	II _{OSB} I	V _{ID} = ±100mV, V _{OUT} = V OUT (Note 4)			5.0	12	mA
SUPPLY CURRENT							
Supply Current	Icc	$R_L = 100\Omega$, $EN_{_} = V_{CC}$			68	98	mA

AC ELECTRICAL CHARACTERISTICS

 $(V_{CC} = 3.0 \text{V to } 3.6 \text{V, } f_{\text{IN}} \leq 1.34 \text{GHz, } t_{\text{R_IN}} = t_{\text{F_IN}} = 125 \text{ps, } R_{\text{L}} = 100 \Omega \pm 1\%, \ |V_{\text{IDI}}| \geq 150 \text{mV, } V_{\text{CM}} = 0.075 \text{V to } (V_{\text{CC}} - 0.6 \text{V}) \text{ (MAX9392 only), } V_{\text{CM}} = 0.6 \text{V to } (V_{\text{CC}} - 0.075 \text{V)} \text{ (MAX9393 only), } EN_{\text{L}} = V_{\text{CC}}, T_{\text{A}} = -40 ^{\circ}\text{C to } +85 ^{\circ}\text{C, unless otherwise noted.}$ Typical values are at $V_{\text{CC}} = 3.3 \text{V, } |V_{\text{IDI}}| = 0.2 \text{V, } V_{\text{CM}} = 1.2 \text{V, } f_{\text{IN}} = 1.34 \text{GHz, } T_{\text{A}} = +25 ^{\circ}\text{C, unless otherwise noted.}$ (Note 5)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
SEL to Switched Output	tswitch	Figure 3			1.1	ns
Disable Time to Differential Output Low	tPHD	Figure 4			1.7	ns
Enable Time to Differential Output High	tpDH	Figure 4			1.7	ns
Switching Frequency	f _{MAX}	V _{OD} ≥ 250mV	1.5	2.2		GHz
Low-to-High Propagation Delay	tplh	Figures 1, 5	294	410	574	ps
High-to-Low Propagation Delay	tphl	Figures 1, 5	286	402	555	ps
Pulse Skew ItpLH - tpHLI	tskew	Figures 1, 5 (Note 6)		17	104	ps
Output-to-Output Skew	tccs	Figures 5, 6 (Note 7)		4	67	ps
Output Low-to-High Transition Time (20% to 80%)	t _R	Figures 1, 5; f _{IN} = 100MHz	112	142	185	ps
Output High-to-Low Transition Time (80% to 20%)	tF	Figures 1, 5; f _{IN} = 100MHz	112	145	185	ps
Added Random Jitter	t _{RJ}	f _{IN_} = 1.34GHz, clock pattern (Note 8)		·	2	psRMS
Added Deterministic Jitter	t _D J	1.34Gbps, 2 ²³ - 1 PRBS (Note 8)		60	98	psp-p

- Note 1: Measurements obtained with the device in thermal equilibrium. All voltages referenced to GND except V_{ID}, V_{OD}, and Δ V_{OD}.
- Note 2: Current into the device defined as positive. Current out of the device defined as negative.
- Note 3: DC parameters tested at T_A = +25°C and guaranteed by design and characterization for T_A = -40°C to +85°C.
- Note 4: Current through either output.
- Note 5: Guaranteed by design and characterization. Limits set at ±6 sigma.
- Note 6: tskew is the magnitude difference of differential propagation delays for the same output over same conditions. tskew = ltpHL tpLHl.
- **Note 7:** Measured between outputs of the same device at the signal crossing points for a same-edge transition, under the same conditions.
- Note 8: Device jitter added to the differential input signal.

MIXIM

Typical Operating Characteristics

vs. TEMPERATURE

tF

10

TEMPERATURE (°C)

MAX9393

vs. TEMPERATURE

TEMPERATURE (°C)

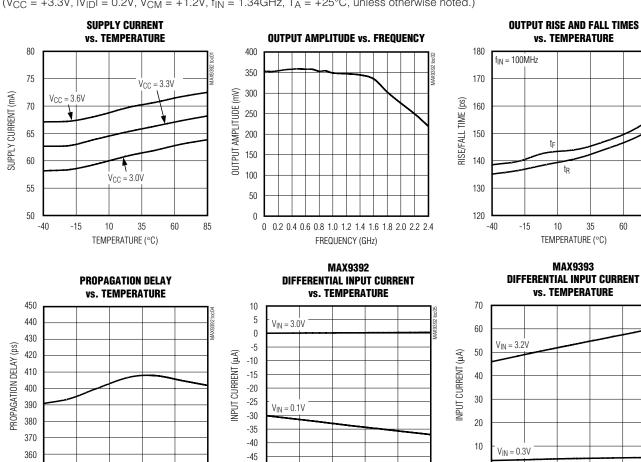
35

60

85

-15

 $(V_{CC} = +3.3V, IV_{ID}I = 0.2V, V_{CM} = +1.2V, f_{IN} = 1.34GHz, T_A = +25^{\circ}C, unless otherwise noted.)$



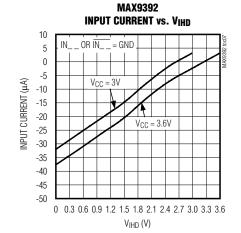
-50

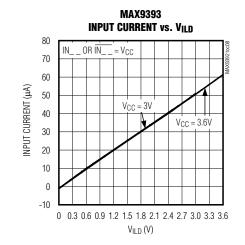
-40

-15

10

TEMPERATURE (°C)





0

-40

-15

350

-40

-15

10

35

TEMPERATURE (°C)

Pin Description

PIN	NAME	FUNCTION
1, 12, 20, 25	GND	Ground
2	INB0	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Noninverting Input. An internal 128k Ω resistor to V _{CC} pulls the input high when unconnected (MAX9392). An internal 68k Ω resistor to GND pulls the input low when unconnected (MAX9393).
3	ĪNB0	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Inverting Input. An internal $128k\Omega$ resistor to V_{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
4	BSEL0	Input Select for B0 Output. Selects the differential input to reproduce at the B0 differential outputs. Connect BSEL0 to GND or leave open to select the INB0 $\overline{\text{(INB0)}}$ set of inputs. Connect BSEL0 to V _{CC} to select the INB1 $\overline{\text{(INB1)}}$ set of inputs. An internal 435k Ω resistor pulls BSEL0 low when unconnected.
5, 16, 24, 29	Vcc	Power-Supply Input. Bypass each V _{CC} to GND with 0.1µF and 0.01µF ceramic capacitors. Install both bypass capacitors as close to the device as possible, with the 0.01µF capacitor closest to the device.
6	INB1	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Noninverting Input. An internal $128k\Omega$ resistor to V _{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
7	ĪNB1	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Inverting Input. An internal $128k\Omega$ resistor to V_{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
8	BSEL1	Input Select for B1 Output. Selects the differential input to reproduce at the B1 differential outputs. Connect BSEL1 to GND or leave open to select the INB0 $\overline{\text{(INB0)}}$ set of inputs. Connect BSEL1 to V _{CC} to select the INB1 $\overline{\text{(INB1)}}$ set of inputs. An internal 435k Ω resistor pulls BSEL1 low when unconnected.
9	ENB1	B1 Output Enable. Drive ENB1 high to enable the B1 LVDS outputs. An internal $435k\Omega$ resistor pulls ENB1 low when unconnected.
10	OUTB1	B1 LVDS Inverting Output. Connect a 100Ω termination resistor between OUTB1 and $\overline{\text{OUTB1}}$ at the receiver inputs to ensure proper operation.
11	OUTB1	B1 LVDS Noninverting Output. Connect a 100Ω termination resistor between OUTB1 and $\overline{\text{OUTB1}}$ at the receiver inputs to ensure proper operation.
13	ENB0	B0 Output Enable. Drive ENB0 high to enable the B0 LVDS outputs. An internal $435 k\Omega$ resistor pulls ENB0 low when unconnected.
14	OUTB0	B0 LVDS Inverting Output. Connect a 100Ω termination resistor between OUTB0 and $\overline{\text{OUTB0}}$ at the receiver inputs to ensure proper operation.
15	OUTB0	B0 LVDS Noninverting Output. Connect a 100Ω termination resistor between OUTB0 and $\overline{\text{OUTB0}}$ at the receiver inputs to ensure proper operation.

Pin Description (continued)

PIN	NAME	FUNCTION
17	ENA1	A1 Output Enable. Drive ENA1 high to enable the A1 LVDS outputs. An internal $435k\Omega$ resistor pulls ENA1 low when unconnected.
18	OUTA1	A1 LVDS Inverting Output. Connect a 100Ω termination resistor between OUTA1 and $\overline{\text{OUTA1}}$ at the receiver inputs to ensure proper operation.
19	OUTA1	A1 LVDS Noninverting Output. Connect a 100Ω termination resistor between OUTA1 and $\overline{\text{OUTA1}}$ at the receiver inputs to ensure proper operation.
21	ENA0	A0 Output Enable. Drive ENA0 high to enable the A0 LVDS outputs. An internal $435 k\Omega$ resistor pulls ENA0 low when unconnected.
22	OUTA0	A0 LVDS Inverting Output. Connect a 100Ω termination resistor between OUTA0 and $\overline{\text{OUTA0}}$ at the receiver inputs to ensure proper operation.
23	OUTA0	A0 LVDS Noninverting Output. Connect a 100Ω termination resistor between OUTA0 and $\overline{\text{OUTA0}}$ at the receiver inputs to ensure proper operation.
26	INA0	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Noninverting Input. An internal $128k\Omega$ resistor to V_{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
27	ĪNA0	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Inverting Input. An internal $128k\Omega$ resistor to V_{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
28	ASEL0	Input Select for A0 Output. Selects the differential input to reproduce at the A0 differential outputs. Connect ASEL0 to GND or leave open to select the INA0 $\overline{\text{(INA0)}}$ set of inputs. Connect ASEL0 to V _{CC} to select the INA1 $\overline{\text{(INA1)}}$ set of inputs. An internal 435k Ω resistor pulls ASEL0 low when unconnected.
30	INA1	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Noninverting Input. An internal $128k\Omega$ resistor to V_{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
31	ĪNA1	LVDS/HSTL (MAX9392) or LVPECL/CML (MAX9393) Inverting Input. An internal $128k\Omega$ resistor to V_{CC} pulls the input high when unconnected (MAX9392). An internal $68k\Omega$ resistor to GND pulls the input low when unconnected (MAX9393).
32	ASEL1	Input Select for A1 Output. Selects the differential input to reproduce at the A1 differential outputs. Connect ASEL1 to GND or leave open to select the INA0 ($\overline{\text{INA0}}$) set of inputs. Connect ASEL1 to V _{CC} to select the INA1 ($\overline{\text{INA1}}$) set of inputs. An internal 435k Ω resistor pulls ASEL1 low when unconnected.

6 ______ NIXI/M

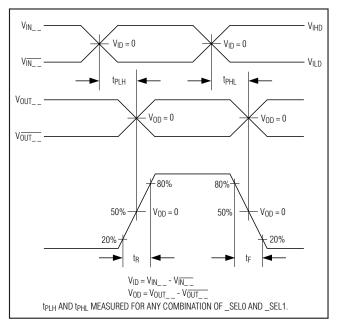


Figure 1. Output Transition Time and Propagation Delay Timing Diagram

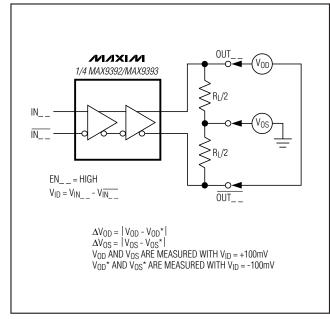


Figure 2. Test Circuit for VOD and VOS

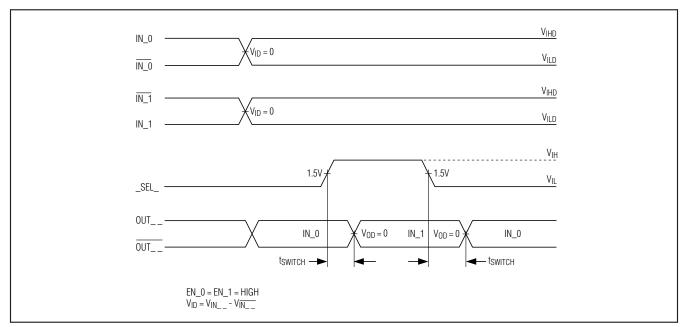


Figure 3. Input to Rising/Falling Edge Select and Mux Switch Timing Diagram

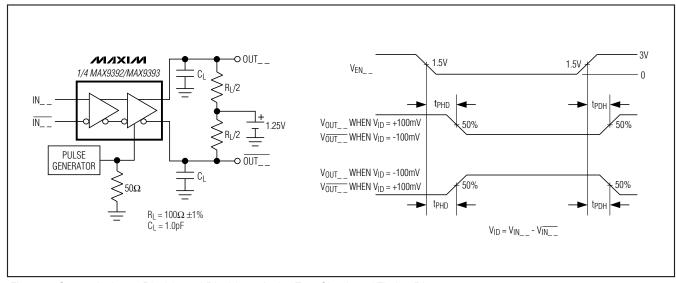


Figure 4. Output Active-to-Disable and Disable-to-Active Test Circuit and Timing Diagram

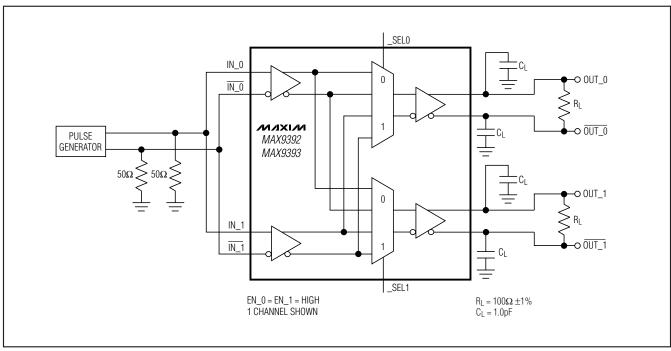


Figure 5. Output Transition Time, Propagation Delay, and Output Channel-to-Channel Skew Test Circuit

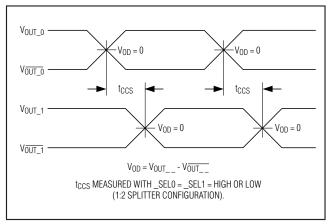


Figure 6. Output Channel-to-Channel Skew

Detailed Description

The LVDS interface standard provides a signaling method for point-to-point communication over a controlled-impedance medium as defined by the ANSI TIA/EIA-644 standard. LVDS utilizes a lower voltage swing than other communication standards, achieving higher data rates with reduced power consumption, while reducing EMI emissions and system susceptibility to noise.

The MAX9392/MAX9393 1.5GHz dual 2 x 2 crosspoint switches optimize high-speed, low-power, point-to-point interfaces. The MAX9392 accepts LVDS and HSTL signals, while the MAX9393 accepts LVPECL and CML signals. Both devices route the input signals to either or both LVDS outputs.

When configured as a 1:2 splitter, the outputs repeat the selected inputs. This configuration creates copies of signals for protection switching. When configured as a repeater, the device operates as a two-channel buffer. Repeating restores signal amplitude, allowing isolation of media segments or longer media drive. When configured as a 2:1 mux, select primary or backup signals to provide a protection-switched, fault-tolerant application.

Input Fail-Safe

The differential inputs of the MAX9392/MAX9393 possess internal fail-safe protection. Fail-safe circuitry forces the outputs to a differential low condition for undriven inputs or when the common-mode voltage exceeds the specified range. The MAX9392 provides high-level input fail-safe detection for LVDS, HSTL, and other GND-referenced differential inputs. The MAX9393 provides low-level input fail-safe detection for LVPECL, CML, and other VCC-referenced differential inputs.

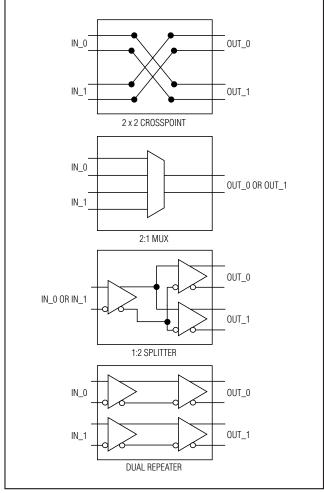


Figure 7. Programmable Configurations

Select Function

The _SEL_ logic inputs control the input and output signal connections. Two logic inputs control the signal routing for each channel. _SEL0 and _SEL1 allow the devices to be configured as a differential crosspoint switch, 2:1 mux, dual repeater, or 1:2 splitter (Figure 7). See Table 1 for mode-selection settings (insert A or B for the _). Channels A and B possess separate select inputs, allowing different configurations for each channel.

Enable Function

The EN_ logic inputs enable and disable each set of differential outputs. Connect EN_ 0 to VCC to enable the OUT_0/OUT_0 differential output pair. Connect EN_0 to GND to disable the OUT_0/OUT_0 differential output pair. The differential output pairs assert to a differential low condition when disabled.

Table 1. Input/Output Function Table

_SEL0	_SEL1	OUT_0 / OUT_0	OUT_1 / OUT_1	MODE
0	0	IN_0 / IN_0	IN_0 / I N_0	1:2 splitter
0	1	IN_0 / I N_0	IN_1 / IN_1	Repeater
1	0	IN_1 / IN_1	IN_0 / I N_0	Switch
1	1	IN_1 / IN_1	IN_1 / IN_1	1:2 splitter

Applications Information

Differential Inputs

The MAX9392/MAX9393 inputs accept any differential signaling standard within the specified common-mode voltage range. The fail-safe feature detects common-mode input signal levels and generates a differential output low condition for undriven inputs or when the common-mode voltage exceeds the specified range. Leave unused inputs unconnected or connect to V_{CC} for the MAX9392 or to GND for the MAX9393.

Differential Outputs

The output common-mode voltage is not properly established if the LVDS output is higher than 0.6V when the supply voltage is ramping up at power-on. This condition can occur when an LVDS output drives an LVDS input on the same chip. To avoid this situation for the MAX9392/MAX9393, connect a $10k\Omega$ resistor from the noninverting output (OUT_) to ground, and connect a $10k\Omega$ resistor from the inverting output (OUT_) to ground. These pulldown resistors keep the output below 0.6V when the supply is ramping up (Figure 8).

Expanding the Number of LVDS Output Ports

Cascade devices to make larger switches. Consider the total propagation delay and total jitter when determining the maximum allowable switch size.

Power-Supply Bypassing

Bypass each VCC to GND with high-frequency surface-mount ceramic $0.1\mu F$ and $0.01\mu F$ capacitors in parallel as close to the device as possible. Install the $0.01\mu F$ capacitor closest to the device.

Differential Traces

Input and output trace characteristics affect the performance of the MAX9392/MAX9393. Connect each input and output to a 50Ω characteristic impedance trace. Maintain the distance between differential traces and eliminate sharp corners to avoid discontinuities in differential impedance and maximize common-mode noise immunity. Minimize the number of vias on the differential input and output traces to prevent impedance

discontinuities. Reduce reflections by maintaining the 50Ω characteristic impedance through connectors and across cables. Minimize skew by matching the electrical length of the traces.

Output Termination

Terminate LVDS outputs with a 100Ω resistor between the differential outputs at the receiver inputs. LVDS outputs require 100Ω termination for proper operation.

Ensure that the output currents do not exceed the current limits specified in the *Absolute Maximum Ratings*. Observe the total thermal limits of the MAX9392/MAX9393 under all operating conditions.

Cables and Connectors

Use matched differential impedance for transmission media. Use cables and connectors with matched differential impedance to minimize impedance discontinuities. Avoid the use of unbalanced cables. Balanced cables such as twisted pair offer superior signal quality and tend to generate less EMI due to canceling effects.

Board Layout

Use a four-layer printed circuit (PC) board providing separate signal, power, and ground planes for high-speed signaling applications. Bypass V_{CC} to GND as close to the device as possible. Install termination resistors as close to receiver inputs as possible. Match the electrical length of the differential traces to minimize signal skew.

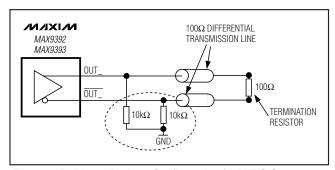
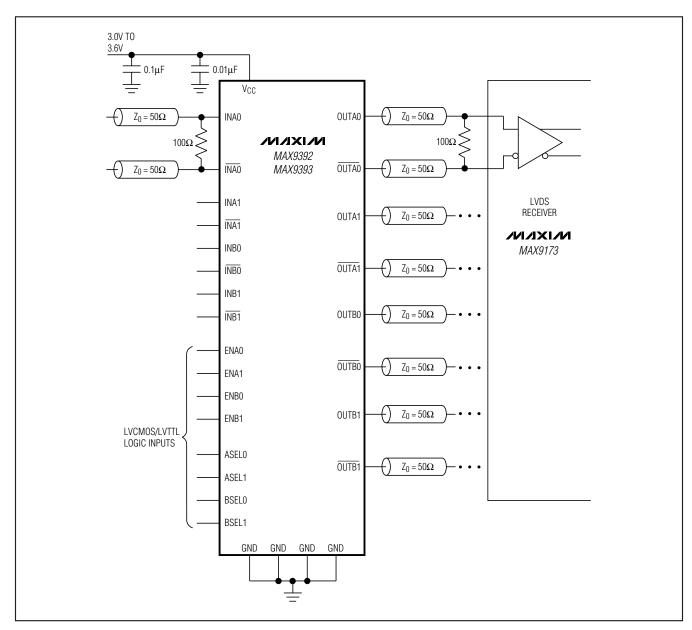


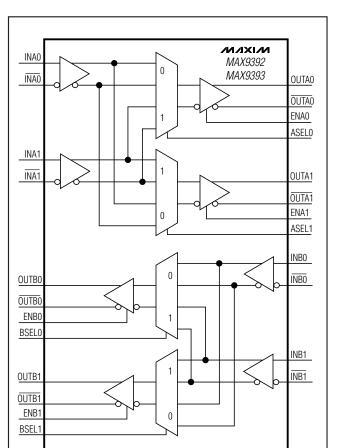
Figure 8. Pulldown Resistor Configuration for LVDS Outputs

10 _______/V|X|/V|

Typical Operating Circuit



Functional Diagram

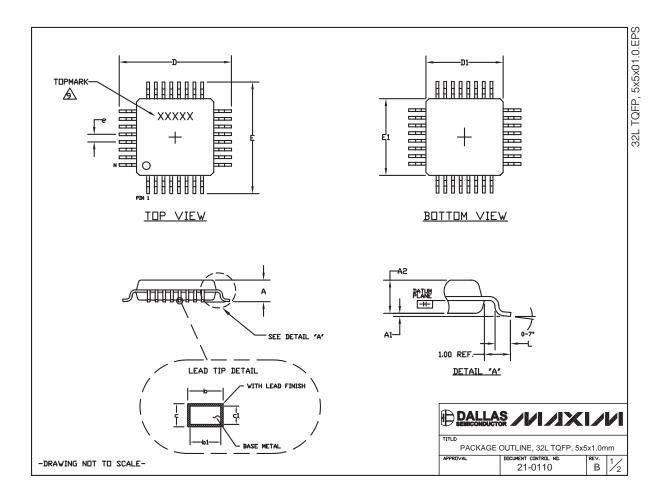


_Chip Information

TRANSISTOR COUNT: 1565 PROCESS: BIPOLAR

Package Information

(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information go to www.maxim-ic.com/packages.)



Package Information (continued)

(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information go to www.maxim-ic.com/packages.)

- NOTES:

 1. ALL DIMENSIONING AND TOLERANCING CONFORM TO ANSI Y14.5-1982.

 2. DATUM PLANE EHE IS LOCATED AT MOLD PARTING LINE AND COINCIDENT WITH LEAD, WHERE LEAD EXITS PLASTIC BODY AT BOTTOM OF PARTING LINE.

 3. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION.
 ALLOWABLE MOLD PROTRUSION IS 0.25 MM ON D1 AND E1
- DIMENSIONS.
 THE TOP OF PACKAGE IS SMALLER THAN THE BOTTOM OF PACKAGE BY 0.15 MILLIMETERS.
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 MM TOTAL IN EXCESS OF THE 6 DIMENSION AT MAXIMUM MATERIAL CONDITION.

 ALL DIMENSIONS ARE IN MILLIMETERS.

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A ₁	0.05 0.15			
A2	0.95 1.05			
D	6.80	7.20		
D ₁	4.80	5.20		
Ε	6.80	7.20		
E ₁	4.80	5.20		
L	0.45	0.75		
N	3	2		
6	0.50 BSC.			
р	0.17	0.27		
b1	0.17	0.23		
U	0.09	0.20		
c 1	0.09 0.16			

DALLAS ////XI//I PACKAGE OUTLINE, 32L TQFP, 5x5x1.0mm DOCUMENT CONTROL NO 21-0110 В

-DRAWING NOT TO SCALE-

Revision History

Pages changed at Rev 1: 1-4, 6, 8, 10-14

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